


<b>Search Notes</b> 	<b>Application/Control No.</b> 10550009	<b>Applicant(s)/Patent Under Reexamination</b> CHEN ET AL.
	<b>Examiner</b> KAMRAN AFSHAR	<b>Art Unit</b> 2617

SEARCHED			
Class	Subclass	Date	Examiner
455	450-453, 422.1-425, 428, 445, 560-561, 550.1, 517	9/16/2007	KA
370	328, 338, 395.1, 395.52, 351-356, 401, 386	9/16/2007	KA

SEARCH NOTES		
Search Notes	Date	Examiner
East Search (US-PGPUB; USPAT; EPO; DERWENT; IBM TDB)	9/16/2007	KA
William Trost	9/16/2007	KA
Ferris Derric	10/22/2007	KA
George Eng, Charls Appiah (Double patenting)	10/22/2007	KA
Updated East Search	12/11/2007	KA
Updated East Search	4/22/2008	KA
John Peng, 101 and new matter	4/22/2008	KA
John Peng, 101 and new matter	11/6/2008	KA
Updated East Search	11/10/2008	KA

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/K. A./  
Examiner, Art Unit 2617